

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APPLICANTS : Toshiyuki NAGAOKA, et al.  
SERIAL NO. : (Unassigned)  
FILED : (Herewith)  
FOR : VARIABLE OPTICAL ELEMENT, OPTICAL UNIT,  
AND IMAGE CAPTURING DEVICE  
GROUP ART UNIT : (Unassigned)  
Examiner : (Unassigned)

COMMISSIONER FOR PATENTS  
P. O. Box 1450  
Alexandria, Virginia 22313-1450

**INFORMATION DISCLOSURE STATEMENT**  
**UNDER 37 C.F.R. § 1.97 & § 1.98**

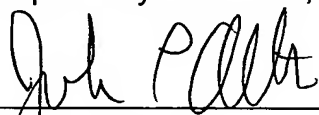
S I R:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

In accordance with the requirements of 37 C.F.R. § 1.98, copies of the references are submitted herewith.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

  
\_\_\_\_\_  
John C. Altmiller  
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Dated: 12 April 2004

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**FORM PTO-1449**  
**INFORMATION DISCLOSURE**  
**STATEMENT BY APPLICANT(S)**

Atty Docket No. : 12706/11  
 Serial No. :  
 Inventors : T. NAGAOKA, et al.  
 Filed :  
 Group Art Unit :  
 Examiner :

**U.S. PATENT DOCUMENTS**

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Patent Date</u>	<u>Name</u>	<u>Class/ Subclass</u>	<u>Filing Date</u>
	2002/0176148	11/28/02	ONUKE et al.	359/253	

**FOREIGN PATENT DOCUMENTS**

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>	<u>Class/ Subclass</u>	<u>Translation Yes No</u>
	2001-249261	09/14/01	Japan		ABS.
	2001-249203	09/14/01	Japan		ABS.

**OTHER DOCUMENTS**

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner  
Initial

1. Claude GABAY et al.: *Dynamic study of a Varioptic variable focal lens*, Current Developments in Lens Design and Optical Engineering III, Proceedings of SPIE Vol. 4767, 2002

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.